

<b>Notice of References Cited</b>		Application/Control No. 10/614,171	Applicant(s)/Patent Under Reexamination WANG ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,419,252	07-2002	Park et al.	280/237
*	B	US-6,390,487	05-2002	Yoo, Moon-Soo	280/237
*	C	US-6,003,889	12-1999	Shalom, Saeed Solomon	280/259
*	D	US-5,924,801	07-1999	Chi, Yi-Chen	384/545
*	E	US-5,884,927	03-1999	Mahaney et al.	280/237
*	F	US-6,386,566	05-2002	Freeberg et al.	280/237
*	G	US-5,626,060	05-1997	Lin, Wen-Hwa	74/594.1
*	H	US-5,597,242	01-1997	Beeler, Douglas C.	384/517
*	I	US-5,473,962	12-1995	Yamamoto, Teiji	74/594.1
*	J	US-5,351,575	10-1994	Overby, Nathan	74/594.2
*	K	US-5,312,125	05-1994	Tsao, Shu	280/287
*	L	US-4,089,540	05-1978	Liljequist, Sten Ivar Helmer	280/259
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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